

National Institute of Technology, Agartala Barjala, Jirania, West Tripura-799046 CENTRAL RESEARCH FACILITY SAMPLE REQUISITION FROM FOR ATOMIC FORCE MICROSCOPY FACILITY

Application No: NITA/CRF/AFM/......Slot Time:.....Slot Date:...../.....

User Information

Name & Design:Candidate: Internal/External Department:......Course:......Course:

Contact No:.....

E-mail address:.....

Contact Address (For External User):

*Internal candidates represent the student's/Staff/Faculty members belong to NIT Agartala.

Instruction

1. No loose powders, corrosive samples, liquid/vapors will be done.

2. One sample will roughly take 30 mins for imaging. Maximum three samples (same material) willbe done in a one slot. Only two samples will be done if materials are different materials.

3. Please do not bring very rough (roughness ~ 1 micron or higher) samples.

- 4. Maximum samples thickness 3 mm.
- 5. Maximum samples dimension 8×8 mm 2.

6. Normally imaging in intermittent contact mode (trapping mode) will be performed. You mighthave to wait for contact mode imaging.

7. Please do not bring samples wrapped in tissue paper/foil. Please bring samples in Petri Dish/sample box. Bring your tweezers. Do not touch sample with hand.

Sample Description

Sample Number	Sample-1	Sample-2	Sample-3
What are you trying to see?			
Expected feature size			

Declaration

I hereby declared that I am using this instrument for my Project/ Research work. I also declared that the above information furnished by me is correct to the best of my knowledge and belief, failure which my application may be terminated for future use. Furthermore I shall be solely responsible if there is any damaging of instrument due to incorrect information provided. Date:

Place:

Signature	Signature with stamp	Signature with stamp
(Student/Scholar)	(Supervisor/Guide/PI)	(HOD)
Payment Details		

For Office Use

The user may be allowed to use the facility as per the procedure. (Any other comments)

Faculty in Charge, CRF, NITA

Chairman, CRF, NITA